What is claimed is:

- 1. An electrostatic chuck to hold a substrate in a process chamber, the electrostatic chuck comprising:
- (a) an electrode comprising a wire loop that extends substantially continuously about a perimeter of the electrode and has a radially outwardly facing surface that is substantially rounded; and
 - (b) a dielectric covering the electrode.
- An electrostatic chuck according to claim 1 wherein the wire loop has a substantially circular cross-section.
- 3. An electrostatic chuck according to claim 2 wherein the substantially circular cross-section has a diameter that is larger than the cross-sectional thickness of the electrode.
- 4. An electrostatic chuck according to claim 1 wherein the electrode comprises a wire mesh.
- 5. An electrostatic chuck according to claim 1 wherein the wire loop has a diameter of at least about 3 micrometers.
- 6. An electrostatic chuck according to claim 1 further comprising a sidewall edge and wherein the current leakage through the sidewall edge is less than about $100 \, \mu A$.
- 7. A substrate processing apparatus for processing a substrate, the substrate processing apparatus comprising:
- (1) a process chamber comprising the electrostatic chuck of claim 1 to hold a substrate in the process chamber;
- (2) a gas distributor to introduce a process gas into the process chamber;
- (3) a gas energizer to energize the process gas in the process chamber to process the substrate; and
- (4) a gas exhaust to exhaust the process gas from the process chamber.

- 8. An electrostatic chuck to hold a substrate in a process chamber, the electrostatic chuck comprising:
 - (a) an electrode comprising:
- (i) a central planar portion comprising a top surface and a bottom surface, and
- (ii) a peripheral arcuate portion having a tip with an upper surface, the arcuate portion having curvature length of at least about $\pi/8$ radians between a normal to the top surface of the central planar portion and a normal to the upper surface of the tip; and
 - (b) a dielectric covering the electrode.
- 9. An electrostatic chuck according to claim 8 wherein the peripheral arcuate portion has a curvature diameter of at least about 3 micrometers.
- 10. An electrostatic chuck according to claim 8 wherein the peripheral arcuate portion the tip of the peripheral arcuate portion extends substantially entirely beyond the bottom surface of the central planar portion.
- 11. An electrostatic chuck according to claim 8 wherein the electrode comprises a wire mesh.
- 12. An electrostatic chuck according to claim 8 further comprising a sidewall edge and wherein the current leakage through the sidewall edge is less than about 100 μ A.
- 13. A substrate processing apparatus for processing a substrate, the substrate processing apparatus comprising:
- (1) a process chamber comprising an electrostatic chuck according to claim 8 to hold a substrate in the process chamber;
- (2) a gas distributor to introduce a process gas into the process chamber;
- (3) a gas energizer to energize the process gas in the process chamber to process the substrate; and
- (4) a gas exhaust to exhaust the process gas from the process chamber.

- 14. An electrostatic chuck to hold a substrate in a process chamber, the electrostatic chuck comprising:
 - (a) an electrode comprising:
- (1) a central planar portion comprising a top surface and a bottom surface; and
- (2) a peripheral arcuate portion having a tip, the arcuate portion having:
- (i) a curvature length of at least about $\pi/8$ radians between a normal to the top surface of the central planar portion and a normal to the upper surface of the tip; and
- (ii) a curvature diameter of at least about 3 micrometers; and
 - (b) a dielectric covering the electrode.
- 15. An electrostatic chuck according to claim 14 further comprising a sidewall edge and wherein the current leakage through the sidewall edge is less than about 100 μ A.
- 16. An electrostatic chuck according to claim 14 wherein the electrode comprises a wire mesh.
- 17. A substrate processing apparatus for processing a substrate, the substrate processing apparatus comprising:
- (a) a process chamber comprising an electrostatic chuck according to claim 14 to hold a substrate in the process chamber;
- (b) a gas distributor to introduce a process gas into the process chamber;
- (c) a gas energizer to energize the process gas in the process chamber to process the substrate; and
- (d) a gas exhaust to exhaust the process gas from the process chamber.